

ICR HV250-75

Near-Field Microprobe 0.5 MHz to 2 GHz



Short description

The probe is used to measure magnetic fields at extremely high resolution and sensitivity. The optimal distance to the object being measured is < 1 mm. Using the ICR HV250-75 a higher output signal in the lower frequency range is generated (in comparison to ICR HV250-6). The measuring coil is vertically aligned within the probe head.

The probe head is shielded against electric field coupling. A preamplifier is integrated in the probe housing, which is powered by the BT 706 bias tee. Adjustment screws on the housing allow manual alignment of the probe tip to the probe housing.

The probe supports the collision protection function of the Langer scanners, which stops the movement during vertical travel if the device under test is touched.

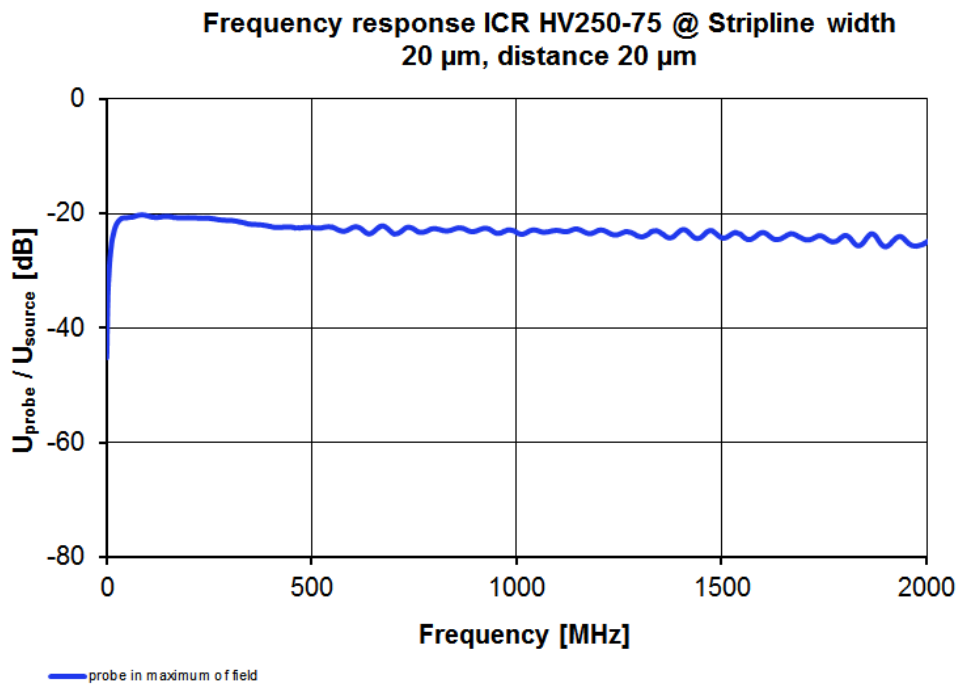
The housing can also be mounted on commercially available testers.

Attention! The tip is very sensitive to impact due to its construction, therefore we recommend positioning the probe through an automatic positioning system.

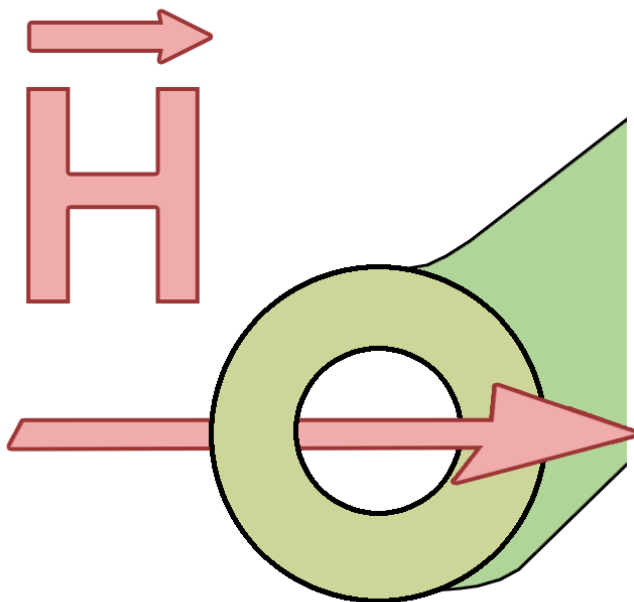
Technical parameters

Frequency range	500 kHz ... 2 GHz
Resolution	110 μ m
Internal diameter	250 μ m

Frequency response

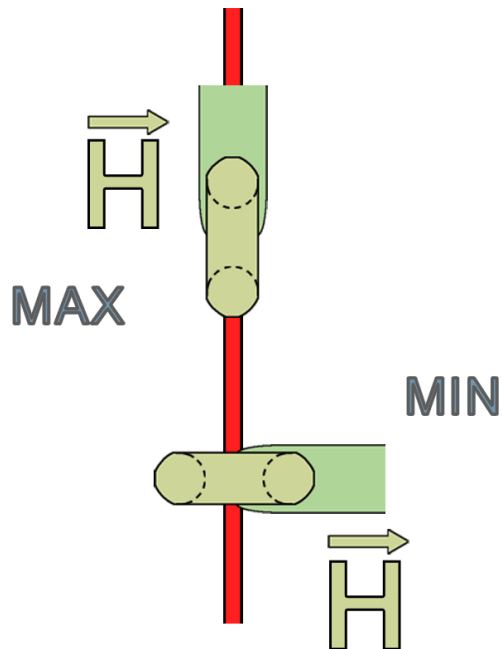


Measuring principles



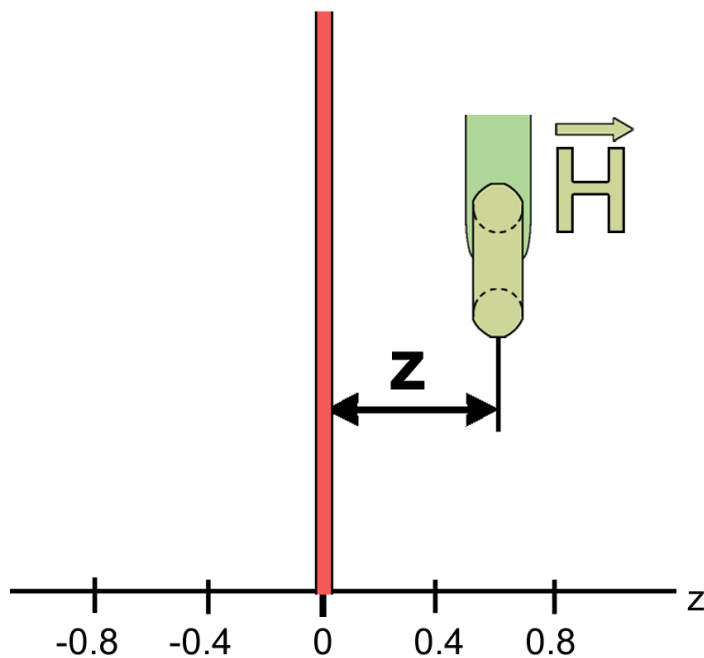
Design, view 1

Stripline



Design, view 2

Stripline



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LANGER
EMV-Technik

Transverse profile

